# Melanie Kirkham

One Bethel Valley Rd. P.O. Box 2008, MS-6460 Oak Ridge, TN 37831-6460 (615) 420-0202 kirkhammj@ornl.gov

# **Education** Georgia Institute of Technology Atlanta, GA

Ph.D. in Materials Science and Engineering, December 2009

Co-Advisors: Dr. Robert L. Snyder and Dr. Zhong Lin Wang

Dissertation: "The Role of the Catalyst in the Growth of One-Dimensional

Nanostructures" Minor in Microbiology

#### University of Tennessee Knoxville, TN

M.S. in Materials Science and Engineering, May 2005

Advisor: Dr. Claudia J. Rawn

Thesis: "Investigation of a Structural Inversion of Pure and MgO- Plus

TiO<sub>2</sub>-Substituted Hexacelsian"

B.S. in Materials Science and Engineering, December 2002

Overall GPA: 3.99/4.00

# University of Wales Swansea, United Kingdom

Exchange Program, September 2000 – June 2001

# **Experience** Oak Ridge National Laboratory Oak Ridge, TN

Scientific Associate, November 2012 – present

- Support experiments at POWGEN Powder Diffractometer (BL-11A) at the Spallation Neutron Source
- Guide users in data collection and analysis
- Train users in safety and beamline procedures
- Ensure safe and efficient operations at POWGEN beamline
- Manage operations and maintenance budget for the beamline
- Oversee and facilitate upgrades in beamline capabilities

#### Postdoctoral Research Associate, January 2010 – November 2012

- Characterized materials for energy applications, including Li-ion battery electrode materials, solid oxide fuel cell materials and thermoelectric materials, including skutterudites, clathrates and intermetallics, with ambient and non-ambient X-ray diffraction
- Guided and collaborated with users from industry, universities and national laboratories to collect and analyze X-ray diffraction data and to present results through conferences and journals
- Designed custom accessory for diffractometer furnace to allow *in-situ* X-ray diffraction from polymer and carbon fibers under tension at elevated temperatures
- Responsible for user training, instrument maintenance and calibration

### Georgia Institute of Technology Atlanta, GA

Graduate Research Assistant, August 2005 – December 2009

- Synthesized nanostructures using catalyzed and non-catalyzed methods

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- Characterized nanostructures with X-ray diffraction and electron microscopy
- Temporarily responsible for X-ray lab, including user training and maintenance for three diffractometers
- Assisted with multiple classes, including teaching lab sessions for materials characterization and X-ray scattering courses

### Oak Ridge National Laboratory Oak Ridge, TN

Postmaster Research Associate, May – August 2005

- Conducted powder XRD experiments on bacterially-reduced, substituted magnetite nanoparticles

#### **University of Tennessee** Knoxville, TN

Graduate Research Assistant, January 2003 - May 2005

- Synthesized ceramics via solid-state and sol-gel methods
- Conducted powder X-ray diffraction experiments on oxides
- Taught practical section of Materials Camp for high-school students
- Taught practical section of "Introduction to Mat. Sci. and Eng." *Undergraduate Research Assistant*, January – September 2002
- Assisted in multiple research projects, including ultra-high cycle fatigue and bulk metallic glasses.

# Honors and Awards

- UT-Battelle Award for Technical Support for Research Team in Science and Technology, Oak Ridge National Laboratory

- Presidential Fellowship, Georgia Tech

### Professional Affiliations

**Professional** - ASM, Intl: National Org. – Volunteerism Comm. (2018 – 2021)

Emerging Professionals Comm. (2012-2015)

Oak Ridge Chapter – Chair (2013-2014), Exec. Comm. (2010-2014)

UTK Student Chapter – Treasurer (2002-2003)

- Neutron Scattering Society of America

#### **Expertise**

- Materials for energy-related applications, including batteries and thermoelectrics
- Neutron powder diffraction
- Thin film and powder X-ray diffraction
- Texture and *in-situ* high temperature XRD measurements
- Rietveld refinement and ab initio structure determination from powder data
- EXPGUI, GSAS-II, and PANalytical suite computer programs